#### **Features**

- 3.0V to 5.5V Operating Range
- Lowest Power in Its Class
- Advanced Low-voltage, Zero-power, Electrically Erasable Programmable Logic Device
- "Zero" Standby Power (25µA Maximum) (Input Transition Detection)
- Low-voltage Equivalent of Atmel ATF22V10CZ
- Ideal for Battery Powered Systems
- CMOS- and TTL-compatible Inputs and Outputs
- Inputs are 5V Tolerant
- Latch Feature Hold Inputs to Previous Logic States
- EE Technology
  - Reprogrammable
  - 100% Tested
- High-reliability CMOS Process
  - 20-year Data Retention
  - 10,000 Erase/Write Cycles
  - 2,000V ESD Protection
  - 200mA Latch-up Immunity
- Commercial and Industrial Temperature Ranges
- Dual Inline and Surface Mount Standard Pinouts
- Green Package Options (Pb/Halide-free/RoHS Compliant) Available

## 1. Description

The Atmel® ATF22LV10CZ/CQZ is a high-performance CMOS (electrically erasable) programmable logic device (PLD) that utilizes The Atmel proven electrically erasable Flash memory technology and provides 25ns speed with standby current of 25µA maximum. All speed ranges are specified over the 3.0V to 5.5V range for industrial and commercial temperature ranges.

The ATF22LV10CZ/CQZ provides a low-voltage and edge-sensing "zero" power CMOS PLD solution with "zero" standby power (5µA typical). The ATF22LV10CZ/CQZ powers down automatically to the zero power mode through The Atmel patented Input Transition Detection (ITD) circuitry when the device is idle. The ATF22LV10CZ/CQZ is capable of operating at supply voltages down to 3.0V. Pin "keeper" circuits on input and output pins hold pins to their previous logic levels when idle, which eliminate static power consumed by pull-up resistors. The "CQZ" combines this low high-frequency ICC of the "Q" design with the "Z" feature.

The ATF22LV10CZ/CQZ macrocell incorporates a variable product term architecture. Each output is allocated from 8 to 16 product terms which allows highly complex logic functions to be realized. Two additional product terms are included to provide synchronous reset and asynchronous reset. These additional product terms are common to all ten registers and are automatically cleared upon power-up. Register Preload simplifies testing. A security fuse prevents unauthorized copying of programmed fuse patterns.



# High-performance Electrically Erasable Programmable Logic Device

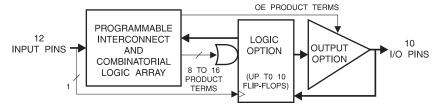
Atmel ATF22LV10CZ Atmel ATF22LV10CQZ

ATF22LV10CZ is Not Recommended for New Design. Replaced by ATF22LV10CQZ.





Figure 1-1. Block Diagram



# 2. Pin Configurations

 Table 2-1.
 Pin Configurations (All Pinouts Top View)

Pin Name	Function
CLK	Clock
IN	Logic Inputs
I/O	Bi-directional Buffers
GND	Ground
VCC	(3 to 5.5V) Supply

Figure 2-1. TSSOP

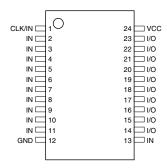


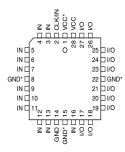
Figure 2-2. DIP/SOIC

		$\bigcirc$		1
CLK/IN □	1		24	□ vcc
IN 🗆	2		23	□ I/O
IN 🗆	3		22	□ 1/0
IN 🗆	4		21	□ I/O
IN □	5		20	□ I/O
IN 🗆	6		19	□ I/O
IN 🗆	7		18	□ I/O
IN 🗆	8		17	1/0
IN 🗆	9		16	1/0
IN 🗆	10		15	□ I/O
IN 🗆	11		14	□ 1/0
GND □	12		13	□IN

Note: TSSOP is the smallest package of SPLD offering

Figure 2-3. PLCC

2



Note: For PLCC, pins 1, 8, 15, and 22 can be left unconnected. For superior performance, connect VCC to pin 1 and GND to pins 8, 15, and 22

# 3. Absolute Maximum Ratings\*

Temperature under Bias40°C to +85°C
Storage Temperature65°C to +150°C
Voltage on Any Pin with Respect to Ground2.0V to +7.0V <sup>(1)</sup>
Voltage on Input Pins with Respect to Ground during Programming2.0V to +14.0V <sup>(1)</sup>
Programming Voltage with Respect to Ground2.0V to +14.0V <sup>(1)</sup>

\*NOTICE:

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

Note:

1. Minimum voltage is -0.6V DC, which may undershoot to -2.0V for pulses of less than 20ns. Maximum output pin voltage is  $V_{\rm CC}$  + 0.75V DC, which may overshoot to 7.0V for pulses of less than 20ns.

# 4. DC and AC Operating Conditions

	Commercial	Industrial
Operating Temperature (Ambient)	0·C - 70·C	-40·C - 85·C
V <sub>CC</sub> Power Supply	3.0V - 5.5V	3.0V - 5.5V





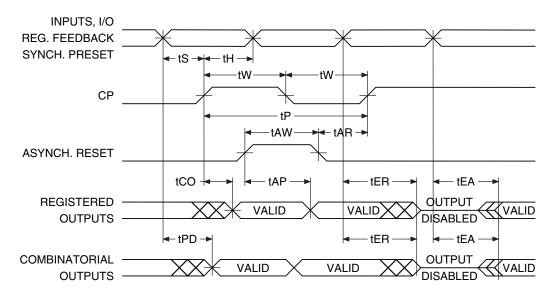
#### 4.1 DC Characteristics

Symbol	Parameter	Condition <sup>(2)</sup>			Min	Тур	Max	Units
I <sub>IL</sub>	Input or I/O Low Leakage Current	$0 \le V_{IN} \le V_{IL} (Max)$					-10.0	μΑ
I <sub>IH</sub>	Input or I/O High Leakage Current	$(V_{CC} - 0.2)V \le V_{IN}$	≤ V <sub>CC</sub>				10.0	μΑ
			CZ-25 <sup>(3)</sup>	Com.		50.0	85.0	mA
	Clocked Power	V <sub>CC</sub> = Max	CZ-25 <sup>(3)</sup>	Ind.		55.0	90.0	mA
I <sub>CC</sub>	Supply Current	Outputs Open, f = 15MHz	CQZ-30	Com.		18.0	50.0	mA
			CQZ-30	Ind.		19.0	60.0	mA
	Power Supply Current, Standby		CZ-25 <sup>(3)</sup>	Com.		3.0	25.0	μA
. P		V <sub>CC</sub> = Max V <sub>IN</sub> = Max Outputs Open	CZ-25 <sup>(3)</sup>	Ind.		4.0	50.0	μΑ
I <sub>SB</sub>			CQZ-30	Com.		3.0	25.0	μA
			CQZ-30	Ind.		4.0	50.0	μΑ
I <sub>OS</sub> <sup>(1)</sup>	Output Short Circuit Current	V <sub>OUT</sub> = 0.5V					-130.0	mA
V <sub>IL</sub>	Input Low Voltage				-0.5		0.8	V
V <sub>IH</sub>	Input High Voltage				2.0		V <sub>CC</sub> + 0.75	V
V <sub>OL</sub>	Output Low Voltage	$V_{IN} = V_{IH} \text{ or } V_{IL}$ $V_{CC} = \text{Min,}$ $I_{OL} = 16\text{mA}$					0.5	V
V <sub>OH</sub>	Output High Voltage	$\begin{aligned} &V_{IN} = V_{IH} \text{ or } V_{IL} \\ &V_{CCIO} = \text{Min,} \\ &I_{OH} = -2.0 \text{mA} \end{aligned}$			2.4			V
V <sub>OH</sub>	Output High Voltage	I <sub>OH</sub> = -100 μA			V <sub>CC</sub> - 0.2V			V

Note:

- 1. Not more than one output at a time should be shorted. Duration of short circuit test should not exceed 30 sec
- 2. For DC characterization, the test condition of  $V_{CC}$  = Max corresponds to 3.6V
- 3. Shaded devices are becoming obsolete and replaced with CQZ-30 part in green package offering

#### 4.2 AC Waveforms



## 4.3 AC Characteristics<sup>(1)</sup>

		-2	<b>-25</b> <sup>(2)</sup>		30	
Symbol	Parameter	Min	Max	Min	Max	Units
t <sub>PD</sub>	Input or Feedback to Non-registered Output	3.0	25.0	10.0	30.0	ns
t <sub>CF</sub>	Clock to Feedback		13.0	10.0	15.0	ns
t <sub>CO</sub>	Clock to Output	2.0	15.0	4.0	20.0	ns
t <sub>S</sub>	Input or Feedback Setup Time	15.0		18.0		ns
t <sub>H</sub>	Input Hold Time	0		0		ns
t <sub>P</sub>	Clock Period	25.0		30.0		ns
t <sub>W</sub>	Clock Width	12.5		15.0		ns
f <sub>MAX</sub>	External Feedback $1/(t_S + t_{CO})$ Internal Feedback $1/(t_S + t_{CF})$ No Feedback $1/(t_P)$	33.3 35.7 40.0			25.0 30.0 33.3	MHz MHz MHz
t <sub>EA</sub>	Input to Output Enable	3.0	25.0	10.0	30.0	ns
t <sub>ER</sub>	Input to Output Disable	3.0	25.0	10.0	30.0	ns
t <sub>AP</sub>	Input or I/O to Asynchronous Reset of Register	3.0	25.0	10.0	3.0	ns
t <sub>SP</sub>	Setup Time, Synchronous Preset	15.0		20.0		ns
t <sub>AW</sub>	Asynchronous Reset Width	25.0		30.0		ns
t <sub>AR</sub>	Asynchronous Reset Recovery Time	25.0		30.0		ns
t <sub>SPR</sub>	Synchronous Preset to Clock Recovery Time	15.0		20.0		ns

Note: 1. See ordering information for valid part numbers

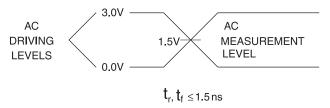
2. Shaded products are becoming obsolete



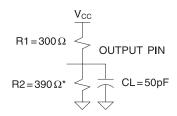


#### 4.4 Input Test Waveforms

#### 4.4.1 Input Test Waveforms and Measurement Levels



#### 4.4.2 Output Test Loads



Note: Similar competitors devices are specified with slightly different loads. These load differences may affect output signals' delay and slew rate. Atmel devices are tested with sufficient margins to meet compatible device specification conditions

#### 4.5 Pin Capacitance

**Table 4-1.** Pin Capacitance (f = 1MHz, T =  $25 \cdot C^{(1)}$ )

	Тур	Max	Units	Conditions
C <sub>IN</sub>	5	8	pF	$V_{IN} = 0V$
C <sub>I/O</sub>	6	8	pF	V <sub>OUT</sub> = 0V

Note: 1. Typical values for nominal supply voltage. This parameter is only sampled and is not 100% tested

#### 4.6 Power-up Reset

6

The registers in the Atmel<sup>®</sup> ATF22LV10CZ/CQZ are designed to reset during power-up. At a point delayed slightly from  $V_{CC}$  crossing  $V_{RST}$ , all registers will be reset to the low state. The output state will depend on the polarity of the buffer.

This feature is critical for state machine initialization. However, due to the asynchronous nature of reset and the uncertainty of how  $V_{CC}$  actually rises in the system, the following conditions are required:

- The V<sub>CC</sub> rise must be monotonic and start below 0.7V
- 2. The clock must remain stable during  $T_{PR}$
- 3. After T<sub>PR</sub>, all input and feedback setup times must be met before driving the clock pin high

#### 4.7 Preload of Register Outputs

The ATF22LV10CZ/CQZ's registers are provided with circuitry to allow loading of each register with either a high or a low. This feature will simplify testing since any state can be forced into the registers to control test sequencing. A JEDEC file with preload is generated when a source file with vectors is compiled. Once downloaded, the JEDEC file preload sequence will be done automatically by most of the approved programmers after the programming.

## 5. Electronic Signature Word

There are 64-bits of programmable memory that are always available to the user, even if the device is secured. These bits can be used for user-specific data.

# 6. Security Fuse Usage

A single fuse is provided to prevent unauthorized copying of the Atmel<sup>®</sup> ATF22LV10CZ/CQZ fuse patterns. Once programmed, fuse verify and preload are inhibited. However, the 64-bit User Signature remains accessible.

The security fuse should be programmed last, as its effect is immediate.

## 7. Programming/Erasing

Programming/erasing is performed using standard PLD programmers. See CMOS PLD Programming Hardware and Software Support for information on software/ programming.

**Table 7-1.** Programming/Erasing

Parameter	Description	Тур	Max	Units
T <sub>PR</sub>	Power-up Reset Time	600	1000	ns
V <sub>RST</sub>	Power-up Reset Voltage	2.3	2.7	V

# 8. Input and I/O Pin Keepers

All ATF22LV10CZ/CQZ family members have internal input and I/O pin-keeper circuits. Therefore, whenever inputs or I/Os are not being driven externally, they will maintain their last driven state. This ensures that all logic array inputs and device outputs are at known states. These are relatively weak active circuits that can be easily overridden by TTL-compatible drivers (see input and I/O diagrams below).

Figure 8-1. Input Diagram

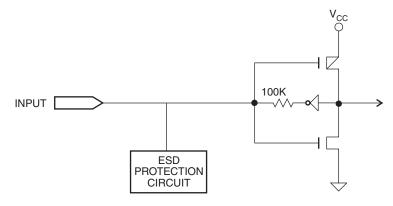
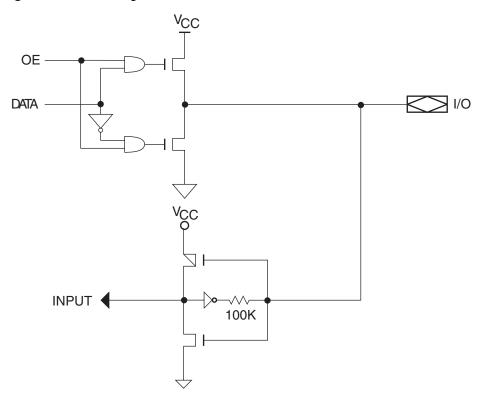




Figure 8-2. I/O Diagram



## 9. Functional Logic Diagram Description

The Functional Logic Diagram describes the Atmel® ATF22LV10CZ/CQZ architecture.

The ATF22LV10CZ/CQZ has 12 inputs and 10 I/O macrocells. Each macrocell can be configured into one of four output configurations: active high/low or registered/combinatorial. The universal architecture of the ATF22LV10CZ/CQZ can be programmed to emulate most 24-pin PAL devices.

Unused product terms are automatically disabled by the compiler to decrease power consumption. A security fuse, when programmed, protects the contents of the ATF22LV10CZ/CQZ. Eight bytes (64-fuses) of User Signature are accessible to the user for purposes such as storing project name, part number, revision or date. The User Signature is accessible regardless of the state of the security fuse.

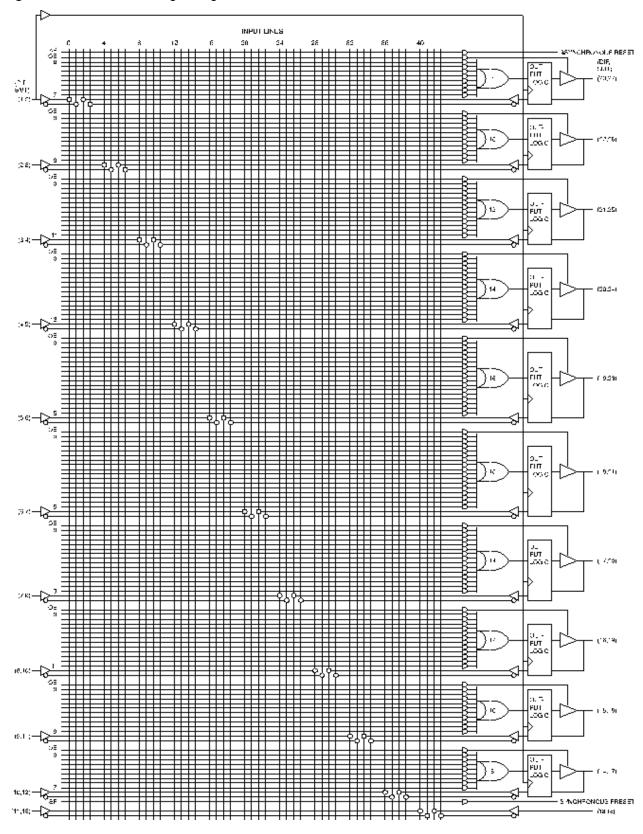
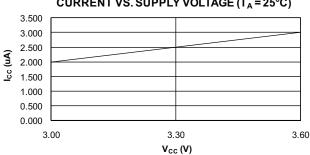


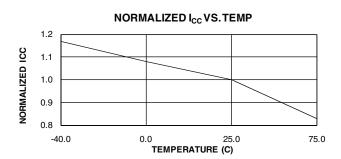
Figure 9-1. Functional Logic Diagram Atmel ATF22LV10CZ/CQZ



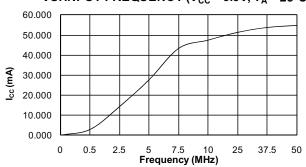


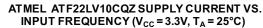


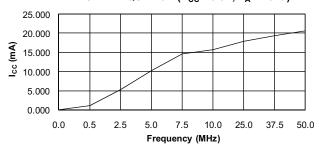




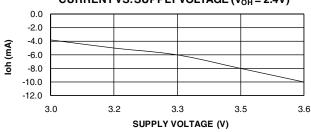
# ATMEL ATF22LV10CZ SUPPLY CURRENT VS. INPUT FREQUENCY ( $V_{CC} = 3.3V$ , $T_A = 25^{\circ}C$ )



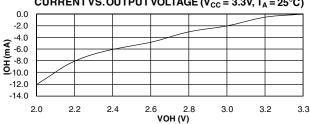




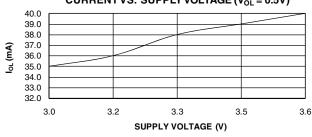
# ATMEL ATF22LV10CZ/CQZ SOURCE CURRENT VS. SUPPLY VOLTAGE ( $V_{OH} = 2.4V$ )



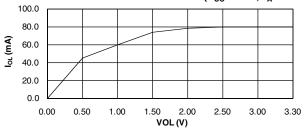




# ATMEL ATF22LV10CZ/CQZ OUTPUT SINK CURRENT VS. SUPPLY VOLTAGE ( $V_{OL} = 0.5V$ )

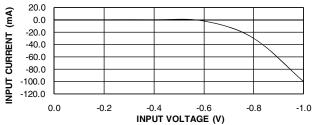


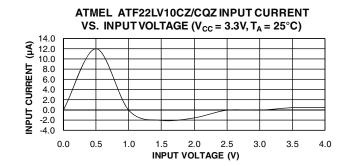
ATMEL ATF22LV10CZ/CQZ OUTPUT SINK CURRENT VS. OUTPUT VOLTAGE (V  $_{CC}$  = 3.3V, T  $_{A}$  = 25  $^{\circ}$  C)

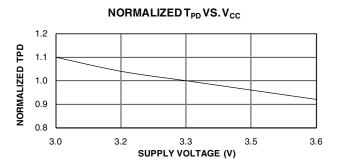


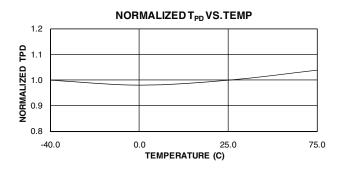
# Atmel ATF22LV10C(Q)Z

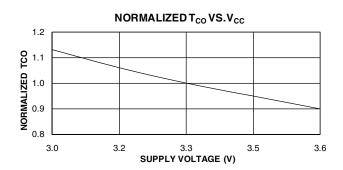
#### ATMEL ATF22LV10CZ/CQZ INPUT CLAMP CURRENT VS. INPUT VOLTAGE ( $V_{CC} = 3.3V, T_A = 25^{\circ}C$ ) 20.0 0.0

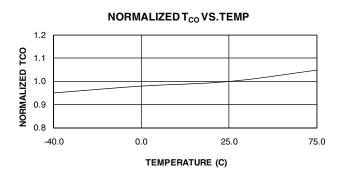


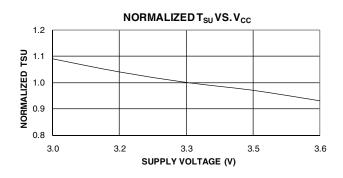


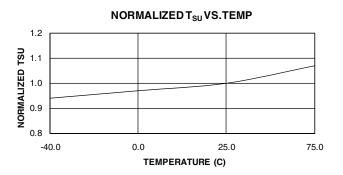






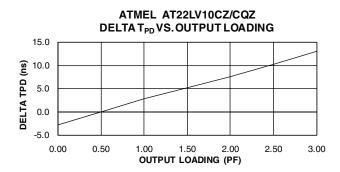


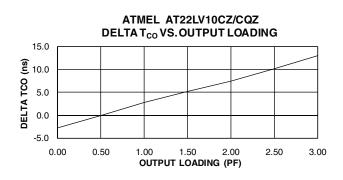


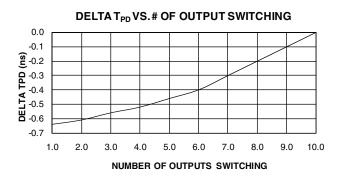


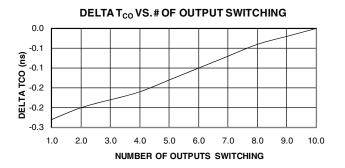












# 10. Ordering Information

# 10.1 Standard Package Options<sup>(1)</sup>

t <sub>PD</sub> (ns)	t <sub>S</sub> (ns)	t <sub>co</sub> (ns)	Ordering Code	Package	Operation Range
			ATF22LV10CZ-25JC ATF22LV10CZ-25PC ATF22LV10CZ-25SC ATF22LV10CZ-25XC	28J 24P3 24S 24X	Commercial (0·C to 70·C)
25	25 15 15	ATF22LV10CZ-25JI ATF22LV10CZ-25PI ATF22LV10CZ-25SI ATF22LV10CZ-25XI	ATF22LV10CZ-25PI ATF22LV10CZ-25SI	28J 24P3 24S 24X	Industrial (-40·C to +85·C)
20		13	ATF22LV10CQZ-30JC ATF22LV10CQZ-30PC ATF22LV10CQZ-30SC ATF22LV10CQZ-30XC	28J 24P3 24S 24X	Commercial (0·C to 70·C)
			ATF22LV10CQZ-30JI ATF22LV10CQZ-30PI ATF22LV10CQZ-30SI ATF22LV10CQZ-30XI	28J 24P3 24S 24X	Industrial (-40·C to +85·C)

Notes: 1. Shaded devices are becoming obsolete and replaced with CQZ-30 parts in green product/package options listed below.

# 10.2 Atmel ATF22LV10CQZ Green Package Options (Pb/Halide-free/RoHS Compliant)

t <sub>PD</sub> (ns)	t <sub>S</sub> (ns)	t <sub>co</sub> (ns)	Ordering Code	Package	Operating Range
30	15	15	ATF22LV10CQZ-30JU ATF22LV10CQZ-30PU ATF22LV10CQZ-30SU ATF22LV10CQZ-30XU	28J 24P3 24S 24X	Industrial (-40·C to +85·C)

### 10.3 Using "C" Product for Industrial

To use commercial product for industrial temperature ranges, simply de-rate  $I_{\text{CC}}$  by 15% on the "C" device. No speed de-rating is necessary.

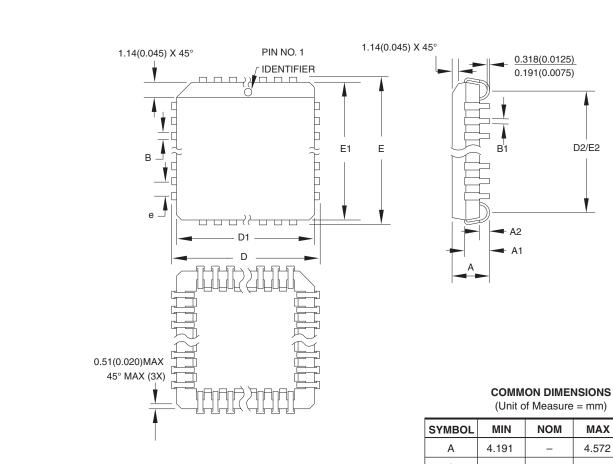
Package Type					
28J	28J 28-lead, Plastic J-leaded Chip Carrier (PLCC)				
24P3	24-pin, 0.300" Wide, Plastic Dual Inline Package (PDIP)				
24S	24-lead, 0.300" Wide, Plastic Gull Wing Small Outline (SOIC)				
24X	24-lead, 4.4 mm Wide, Plastic Thin Shrink Small Outline (TSSOP)				





# 11. Packaging Information

## 11.1 28J - PLCC



Notes: 1. This package conforms to JEDEC reference MS-018, Variation AB.

- Dimensions D1 and E1 do not include mold protrusion.
   Allowable protrusion is .010"(0.254mm) per side. Dimension D1 and E1 include mold mismatch and are measured at the extreme material condition at the upper or lower parting line.
- 3. Lead coplanarity is 0.004" (0.102mm) maximum.

SYMBOL	MIN	NOM	MAX	NOTE	
Α	4.191	_	4.572		
A1	2.286	_	3.048		
A2	0.508	_	_		
D	12.319	-	12.573		
D1	11.430	_	11.582	Note 2	
Е	12.319	_	12.573		
E1	11.430	_	11.582	Note 2	
D2/E2	9.906	_	10.922		
В	0.660	-	0.813		
B1	0.330	_	0.533		
е		1.270 TYP			

10/04/01

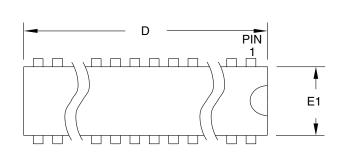
AMEL	Package Drawing Contact:
	Package Drawing Contact: packagedrawings@atmel.com

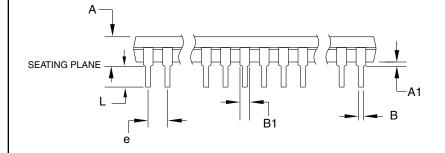
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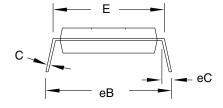
TITLE	
28J, 28-lead, Plastic J-leaded Chip Carrier (PLCC	;)

DRAWING NO.	REV.	
28J	В	

#### 11.2 24P3 - PDIP







Notes:

- 1. This package conforms to JEDEC reference MS-001, Variation AF.
- Dimensions D and E1 do not include mold Flash or Protrusion. Mold Flash or Protrusion shall not exceed 0.25mm (0.010").

#### **COMMON DIMENSIONS**

(Unit of Measure = mm)

SYMBOL	MIN	NOM	MAX	NOTE
Α	_	_	5.334	
A1	0.381	_	_	
D	31.623	_	32.131	Note 2
Е	7.620	_	8.255	
E1	6.096	_	7.112	Note 2
В	0.356	_	0.559	
B1	1.270	_	1.651	
L	2.921	_	3.810	
С	0.203	_	0.356	
eB	-	_	10.922	
eC	0.000	_	1.524	
е		2.540 T	YP	

6/1/04



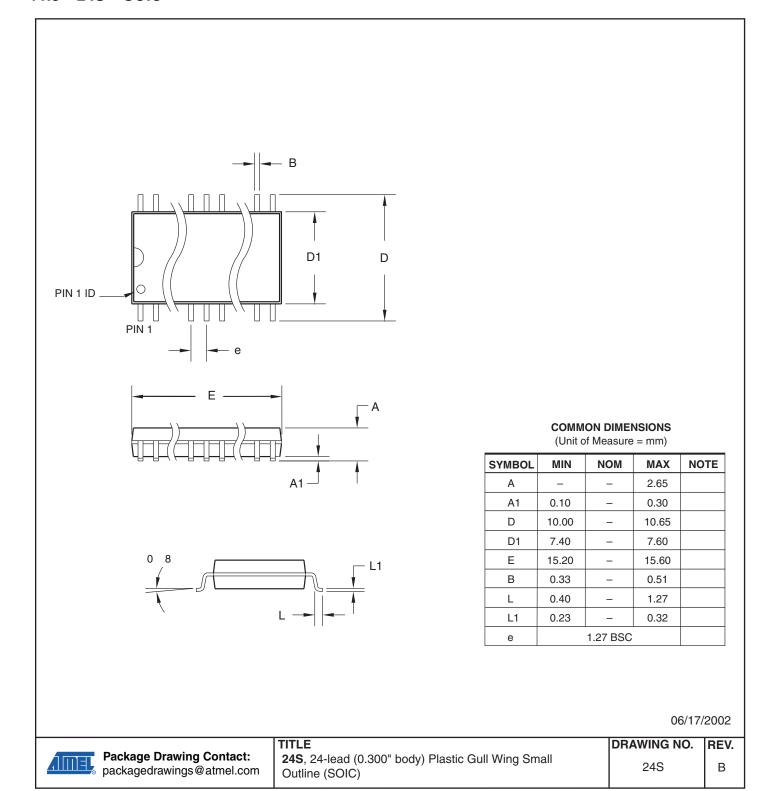
IIILE	
<b>24P3</b> , 24-lead (0.300"/7.62 Inline Package (PDIP)	2mm Wide) Plastic Dual

DRAWING NO. REV. 24P3 D

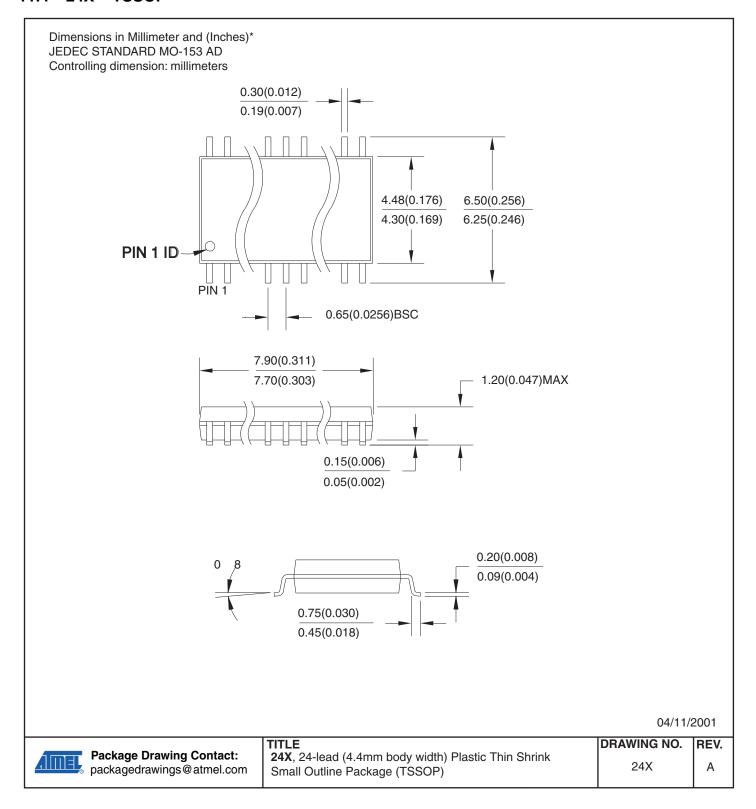




#### 11.3 24S - SOIC



#### 11.4 24X - TSSOP







# 12. Revision History

Doc. Rev.	Date	Comments	
М	07/2010	Atmel ATF22LV10CZ-25JC/JI, PC/PI, SC/SI, XC/XJ leaded parts will become obsolete. 06/2014 The ATF22LV10CZ is obsolete. Replaced by ATF22LV10CZ.	
L	11/2005	Added Green Package options	